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Harry A. ATWATE First Named Inventor TRADE 1764 (76) **Group Art Unit** 0-00 Due <u>Unassigned</u> (use as many sheets as necessary) **Examiner Name** 047071-0107 Sheet of Attorney Docket Number

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INFORMATION DISCLOSURE	Application Number	10/761,918			
P C STATEMENT BY APPLICANT	Filing Date	01/20/2004			
D 2/ 2-1-2-1-14-1-15	First Named Inventor	Harry A. ATWATER et al.			
Date Submitted: 1/6/05	Group Art Unit	1764 1765			
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	Data Sub	mitted: 1/6/	'AE	First Named Inventor	Harry A. ATWATER et al.		
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	Т ⁶
90	A52	ZAHLER et al., Wafer Bonded Ge/Si Heterostructures for Photovoltaic Applications, (Abstract and Presentation), MRS 2002 Spring Meeting (04/2002)	
1	A53	ZAHLER J.M., Materials Integration by Wafer Bonding and Layer Transfer, (Presentation), 13 pages, MRS 2004 Spring Meeting (04/2004)	
	A54	ZAHLER et al., The Role of H in the H-Induced Exfoliation of GE Films, (Abstract and Presentation), MRS 2004 Spring Meeting, 16 pages (04/2004)	
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	INFORMATIO	N DISCLO	SURE	Application Number	10/761,918	
	STATEMENT	BY APPLI	CANT	Filing Date	01/20/2004	
	Data Sub	mitted: 1/6/6	ns.	First Named Inventor	Harry A. ATWATER et al.	
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A61	MORRAL et al., Bonding and Layer Transfer Process of InP on Silicon for the Elaboration of the Botton Double Heterostructure of 4-Junction High Efficiency Solar Cells, (Abstract), MRS 2002 Fall Meeting, (11/2002)	
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